THERMAL MODEL FOR THE SIMPLE MICROBOLOMETER * * This program handles both the steady state 'dc' case and the time dependent * case of a 2 dimensional body. It is written in Fortran 77, to be run * on a Macintosh Plus computer. * The problem is symmetrical, so will only do half, treating the * cut portion as a perfect insulator. * * The method of solving the problem is a finite-difference approach * where thermal resistance elements are used in a Gauss-Seidel * iteration.(see J.P.Holman,Heat Transfer,4th ed.,eqn.4-43(page130). * * NOTE: in this program, column 1 is considered an insulating wall * and column = (COL) is a thermal sink. Row 1 is a perfect * insulator (it is a layer of air above the device), and * row = (ROW) is a thermal sink. The antenna is also a sink. ****** **DEFINITION OF TERMS** ************ * * Detector * (dR/RdT) in $1/^{\circ}K$ alpha heat capacity (µW-sec/°K) of element * CĪdet * kdet thermal conductivity in $W/(cm-{}^{\circ}K)$ * Ldet lengths (um) of the films studied * rhodet density $(g/cm^{**}3)$ * elect resistance at 300K for 1 element Rodet * specific heat, $(cal/(gm-^{\circ}K))$ SHdet * sigdet electical conductivity in $1/(\Omega-cm)$ * detthk film thickness in Å * * Substrate * CIsub heat capacity ($\mu W/(K-sec)$) of element * thermal conductivity in $W/(cm-{}^{\circ}K)$ ksub $length(\mu m)$ of the substrate considered * Lsub * density (g/cm**3) rhosub * specific heat, (cal/(gm-°K))SHsub * thickness of each row in top,bot(Å) subth * * **OPERATING PARAMETERS** * Ibias bias current in mA * Irf radiation current, modulated by sin(wt) * the max Tdev for one iteration maxdev * 1/2 the total bolometer resistance (Ω) SumRe

Appendix A

*	Tamb	ambient temperature °K
*	Tdev	deviation in T(old) with T(new)
*	R0	detector resistance (Ω) with no Irf
*	R0 R1	detector resistance (Ω) at Irf#1
*		
*	Resp	responsivity (V/W)
*	flaga	indicates uniform det. thickness, or not
*	ELEMENT PARAMI	TTERS
*	delx,dely	the finite increments used, in µm
*	DE	the time increment, (sec)
*	DEV	
*	COL	the allowed Temp deviation to quit iterating
*		the total number of increments (columns)
*	fname	filename for output
*	ROW	total number of layers deep
*	N O(V)	the number of increments in the Bi
	Q(X)	heat generated by $I^{**}2^{*}R$, in μW
*	thicktc(X)	thickness of Xth detector element
*	Zx(X,Z)	thermal R($^{\circ}K/\mu W$) in x dir of Mth element
*	Zz(X,Z)	thermal R(°K/ μ W) in z dir of Mth element
*		ctical $R(\Omega)$ of the Mth element
*	CI(X,Z)	heat capacity of an (x,z) element
*	Tm(X,Z)	temperature ($^{\circ}$ K) of (X,Z)th element
*	X,Z,K,user	misc. counters
*	TOP,BOT	variables to hold GSITER intermed. values
*	ORD	max dimension size
*	Ttop	temperary temperature vaiable
*	Ts(X,Z)	temporary temp array
*	Tp(X,Z)	element temp, steady state, and present time
*	TLO,TT,THI	used in iterative routine for isotherm
*	ZRLO,ZRT,ZRHI	ditto
*	XPOS,ZPOS	
*	T	
	-	

* note: the CI and Ts arrays are not used in the steady state analysis.

****	DEFIN	VE VARIABLE TYPES ***************
	Integer ORD,I PARAMETEF PARAMETEF	R(ORD = 30)
* *	VARIABLES For det	
*	Real*8 Real*8	alpha,CIdet,kdet,Ldet,rhodet,Rodet,SHdet sigdet,detthk,R0,R1,thkdet
42	For Substrate Real*8	CIsub,ksub,Lsub,rhosub,SHsub

	Real*8	topsubth,botsubth
	Integer	topsub,botsub
*	For OPERA	TING PARAMETERS
	Real*8	Ibias,Irf,maxdev,Tamb,Tdev
	D 1*0	

101as,111,111aAucv, 1 a1110, 1 ucv
Resp,SumRe,TOP,BOT
COL,ROW
isofname*20,flaga*10

* FOR ELEMENT PARAMETERS Real*8 delx,dely,DEV,ruser Real*8 Xpos,Zpos,T,PI Integer M,N,X,Z,K,user,I,JJ,PRG

* TIME DEPENDENT STUFF

Real*8	th,time,rfI,V,ntime,W,Vpp
Real*8	Vmax,Vmin,Rmax,Rmin,f,DE,totime
Integer	DELAY, DUR, tinc

* initialize arrays

Real*8	Zx(ORD,ORD),Zz(ORD,ORD)
Real*8	ZP(ORD),ISO(ORD,ORD),XP(ORD)
Real*8	CI(ORD,ORD),Tp(ORD,ORD)
Real*8	Q(ORD),thickdet(ORD),RE(ORD)
Real*8	ZD(ORD,ORD),Tm(ORD,ORD)
Real*8	TV(3,1000)

SET DEFAULT VALUES ********

- * Detector:
 - alpha = -.003kdet = 0.040Ldet = 2.0rhodet = 9.80SHdet = 0.30sigdet = 1100. detthk = 1000.0
- * Substrate:
 - ksub = 0.008 rhosub = 2.2 SHsub = 0.180 subth = 2500.0Lsub = 4.0

* OPERATING PARAMETERS:

Ibias = 1.0 Irf = 0.0100 Tamb = 300.0 PI = 3.1415926536 isofname = 'tdmb.dat' flaga = 'row'

* ELEMENT PARAMETERS: DEV = 1.0E-06 COL = 12 ROW = 13dely = 3.5

* TIME DEPENDENT STUFF:

time = 0.0Vmax = 0.Vmin = 1.d9Rmax = 0.Rmin = 1.d9DELAY = 2DUR = 1f = 3.d5DE = 25.d9PRG = 0

5

PROMPT USER FOR NEW DEFAULT VALUES *****
 Write(9,*) 'enter one of the following:'
 Write(9,*) 'change physical parameters [0]'
 WRITE(9,*) 'execute the steady state program [1]'
 WRITE(9,*) 'execute the time dependent program [2]'

[3]'

WRITE(9,*) 'exit the program Read(9,*) user GO TO (10.100.105.600).user + 1

- 10 Write(9,*) 'change: detector: [0]' Write(9,*) ' [1]' substrate: Write(9,*) ' elements/misc: [2]' Write(9,*) ' frequency: [3]' Write(9,*) 'go to starting menu [4]' Read(9,*) user GO TO (15,20,25,30,5),user + 1 GO TO 10
- *** Change detector parameters 15 Write(9,*) 'DETECTOR:' Write(9,*) ' TCR (1/K) = ',alpha Read(9,*) alpha Write(9,*) ' thermal conductivity (W/(cm-K))',kdet Read(9,*) kdet Write(9,*) 'length in μm',Ldet Read(9,*) Ldet

Write(9,*) 'Density (g/cm**3)',rhodet Read(9,*) rhodet Write(9,*) 'specific heat (cal/(g-K))',SHdet Read(9,*) SHdet Write(9,*) 'electrical conductivity (1/ Ω -cm)',sigdet Read(9,*) sigdet Write(9,*) 'film thickness (Å)',detthk Read(9,*) detthk GO TO 10

*** Change substrate parameters 20 Write(9.*) 'SUBSTRATE:'

Write(9,*) 'SUBSTRATE:'
Write(9,*) ' thermal conductivity (W/(cm-K))',ksub
Read(9,*) ksub
Write(9,*) 'length in μm',Lsub
Read(9,*) Lsub
Write(9,*) 'Density (g/cm**3)',rhosub
Read(9,*) rhosub
Write(9,*) 'specific heat (cal/(g-K))',SHsub
Read(9,*) SHsub
Write(9,*) 'substrate layer row thickness:',subth
Read(9,*) subth
GO TO 10

- *** Change element/misc parameters
- Write(9,*) 'ELEMENTS and MISC:' 25 Write(9,*) 'number of columns:',COL Read(9,*) COL Write(9,*) 'number of rows:',ROW Read(9,*) ROW Write(9,*) 'allowed temp deviation:',DEV Read(9,*) DEV Write(9,*) 'delta Y:',dely Read(9,*) dely Write(9,*) 'Bias current (mA):', Ibias Read(9,*) Ibias Write(9,*) 'rf current (mA):',Irf Read(9,*) Irf Write(9,*) 'ambient temperature (K):',Tamb Read(9,*) Tamb Write(9,*) 'filename for isothermal plot: ',isofname Read(9,*) isofname **GO TO 10**

**** change frequency

30 Write(9,*) 'enter modulation frequency:',f Read(9,*) f delx = Lsub/(COL - 2) DE = 625.d-9 * delx**2 tinc = INT(1./(f*DE)) Write(9,*) 'recommend ',tinc,' points/cycle' Write(9,*) 'enter # points/cycle:',tinc Read(9,*) tinc DE = 1./(f*tinc) Write(9,*) 'delay before taking data (cycles):',DELAY Read(9,*) DELAY GO TO 10

***** ******** intitialize arrays *** calculate element values 100 PRG = 1GO TO 110 105 PRG = 2delx = Lsub/(COL - 2)110 N = Int(Ldet/delx)CIdet = rhodet * SHdet * delx * dely * 4.184D-10 CIsub = rhosub*SHsub* delx * dely * 4.184D-10Rodet = (delx * 1.0D+8)/(sigdet*dely*detthk)*** set parameters for insulating walls * (at col=1 and at row=1) (at col=1 and at row=1)X = 1do 115 Z=2,ROW-1 Zx(X,Z) = 1.D12Zz(X,Z) = 1.D12115 continue Z = 1do 120 X=1,COL Zx(X,Z) = 1.D12Zz(X,Z) = 1.D12120 continue *** set parameters for thermal sinks * (at col=COL,row=ROW, and antenna region * where col=N+2 to COL-1) X = COLdo 125 Z=2,ROW-1 Zx(X,Z) = 0.Zz(X,Z) = 0.125 continue Z = ROWdo 130 X=1,COL Zx(X,Z) = 0.Zz(X,Z)=0.130 continue Z = 2

do 135 X=N+2.COL-1 Zx(X,Z) = 0.Zz(X,Z) = 0.135 continue *** set parameters for the detector do 140 X=2,N+1 Zx(X,2) = (delx*100.0)/(kdet*dely*detthk)Zz(X,2) = detthk/(dely*delx*kdet*1.D6)CI(X,2) = CIdet*detthkRE(X) = Rodet140 continue *** set parameters for the substrate do 150 Z=3.ROW-1 do 145 X=2,COL-1 Zx(X,Z) = (delx*100.0)/(ksub*dely*subth)Zz(X,Z) = subth/(dely*delx*ksub*1.D6)CI(X,Z) = CIsub*subth145 continue 150 continue *** initialize arrays do 160 X=1.COL Q(X) = 0.do 155 Z=1,ROW Tm(X,Z) = TambTp(X,Z) = TambZD(X,Z) = 0.155 continue 160 continue ***** FIND STEADY STATE T(X,Z) ******** Write(9,*) 'starting steady state routine' * determine heat generation terms $\mathbf{K} = \mathbf{0}$ 200 maxdev = 0.K = K+1do 205 X=2,N+1 $Q(X) = (Ibias^{**2})^{*}RE(X)$ 205 continue CALL GSITER(ROW,COL,Tm,Zx,Zz,ZD,ZD,DE,Q,TOP,BOT,N, Tdev,maxdev,ORD) +*** calculate new RE(I) do 210 I=2,N+1 RE(I)=Rodet*((alpha*(Tm(I,2)-Tamb))+1.)

210 continue

IF(maxdev .gt. DEV) go to 200 SumRe = 0.0Do 215 X=2,N+1 SumRe = SumRe + RE(X)215 continue R0 = SumReWrite(9,*) 'end of steady state. # iter= ',K Write(9,*) 'steady state full R = ',2.*R0IF(PRG.eq.2) go to 400 $\mathbf{K} = \mathbf{0}$ 220 maxdev = 0.K = K+1do 225 X=2,N+1 $Q(X) = (Ibias^{**2} + PI^{*}(Irf^{**2}))^{*}RE(X)$ 225 continue CALL GSITER(ROW,COL,Tm,Zx,Zz,ZD,ZD,DE,Q,TOP,BOT,N, Tdev,maxdev,ORD) +*** calculate new RE(I) do 230 I=2.N+1 RE(I)=Rodet*((alpha*(Tm(I,2)-Tamb))+1.)230 continue IF(maxdev .gt. DEV) go to 220 Write(9,*) 'end of 2nd steady state. # iter= ',K SumRe = 0.0Do 235 X=2,N+1 SumRe = SumRe + RE(X)235 continue R1 = SumReResp = 2000.*(Ibias*(R1-R0))/(PI*Irf**2*(R0+R1))Write(9,*) 'for Irf= ',Irf,' Resp = ',Resp Write(9,*) 'biased full R = ',2.*R1Write(9,*) char(7)240 Write(9,*) '[0]=new run,[1]=isotherm,[2]=stop' Read(9,*) user GO TO (5,245,600), user + 1 ***** ******** **ISOTHERM ROUTINE** Write(9,*) 'isotherm' 245 first put Xpos and Zpos into arrays * Do 255 X=2, COL-1

- Z = 2Xpos = (X-1.5) * delxXP(X) = XposZpos = .5*td $\overline{ZP}(Z) = Zpos$ Do 250 Z=3,ROW - 1 Zpos = td + (Z-2.5)*ts $\overline{ZP}(Z) = Zpos$ 250 continue 255 continue * find max T THI=Tamb do 265 X=2,COL-1 do 260 Z=2,ROW-1 TS = Tm(X,Z)IF(TS.GT.THI) THEN **THI=TS** END IF 260 continue 265 continue write(9,*) 'peak element temp (K) = ',THI * now run find isotherms Write(9,*) ' enter the target temperature: ',TT Read(9,*) TT Write(9,*) 'filename?' Read(9,*) isofname * initialize ISO array do 275 X=2,COL-1 do 270 Z=1,6 ISO(X,Z) = 0.270 continue 275 continue do 305 X=2,COL-1 M = 1Z = 2TS = Tm(X,Z)IF(TS.GT.TT) THEN GO TO 290 END IF TLO = TSZRLO = ZP(Z)Z = Z + 1280 IF (Z.EQ.ROW) THEN
 - GO TO 305

END IF TS = Tm(X,Z)IF(TS.GT.TT) THEN GO TO 285 END IF IF(TS.GT.TLO) THEN TLO = TSZRLO = ZP(Z)END IF **GO TO 280** 285 THI = TSZRHI = ZP(Z)CALL INTERP(TLO,TT,THI,ZRLO,ZRT,ZRHI) ISO(X,M) = ZRTM=M+1290 THI = TSZRHI = ZP(Z)295 Z = Z + 1IF (Z.EQ.ROW) THEN GO TO 305 END IF TS = Tm(X,Z)IF(TS.LT.TT) THEN **GO TO 300** END IF IF(TS.LT.THI) THEN THI = TSZRHI = ZP(Z)END IF GO TO 295 300 TLO = TSZRLO = ZP(Z)CALL INTERP(TLO,TT,THI,ZRLO,ZRT,ZRHI) ISO(X,M) = ZRTM=M+1**GO TO 280** 305 **CONTINUE** * OUTPUT ISOTHERM DATA TO TEXT FILE 310 OPEN(UNIT=12,FILE=isofname) DO 320 X=2,COL-1 Xpos = XP(X) $Z\overline{1} = ISO(X,1)$ Z2 = ISO(X,2)

- Z3 = ISO(X,3)
- Z4 = ISO(X,4)
- Z5 = ISO(X,5)
- Z6 = ISO(X,6)

```
WRITE(12,315) Xpos,CHAR(9),Z1,CHAR(9),Z2,CHAR(9),
   + Z3,CHAR(9),Z4,CHAR(9),Z5,CHAR(9),Z6
315
      FORMAT(1X,E12.6,a1,E12.6,a1,E12.6,a1,E12.6,a1,
   + E12.6,a1,E12.6,a1,E8.4)
320
      continue
      CLOSE(UNIT=12)
      GO TO 240
*****
             TIME DEPENDENT ROUTINE
                                               ********
400
      time = 0.0
      DE = 1/(f*16.)
      user = DELAY*16 - 1
      do 425 I=1,user
      do 405 JJ=1,REP
      CALL GSITER(ROW,COL,Tp,Zx,Zz,CI,Tm,DE,Q,TOP,BOT,N,
             Tdev, maxdev, ORD)
  +
405
      continue
      do 415 X=1.COL
             do 410 Z=1,ROW
             Tm(X,Z) = Tp(X,Z)
410
             continue
415
      continue
      th = 2*PI*f*time + PI/2.
      A = PI^{*}.250^{*}((\cos(th))^{**}2 + 2^{*}\cos(th) + 1.)
***
      calculate new RE(I)
      do 420 X=2,N+1
      RE(X)=Rodet^{(alpha^{(Tm(X,2)-Tamb))+1.)}
      Q(X) = (Ibias^{**2} + A^{*}Irf^{**2}) * RE(X)
420
      continue
      time = time + DE
      Write (9,*) I,' of ',user
425
      continue
***
      run time dependent loop
***
      start loop; run 1 cycle before taking data
      time = 0.0
      DE = 1./(f*tinc)
      do 450 I=1,tinc
             do 430 JJ=1,REP
      CALL GSITER(ROW,COL,Tp,Zx,Zz,CI,Tm,DE,Q,TOP,BOT,N,
             Tdev,maxdev,ORD)
  +
430
      continue
      do 440 X=1.COL
             do 435 Z=1.ROW
             Tm(X,Z) = Tp(X,Z)
435
             continue
```

440 continue th = 2*PI*f*time + PI/2. $A = PI^*.250^*((\cos(th))^{**}2 + 2^*\cos(th) + 1.)$ *** calculate new RE(I) do 445 X=2,N+1 $RE(X)=Rodet^{(alpha^{(Tm(X,2)-Tamb))+1.)}$ $Q(X) = (Ibias^{**2} + A^{*}Irf^{**2}) * RE(X)$ 445 continue time = time + DEWrite (9,*) I,' of ',tinc 450 continue *** start taking data time = 0.0totime = DUR*tinc do 480 I=1,DUR*tinc do 455 JJ=1,REP CALL GSITER(ROW,COL,Tp,Zx,Zz,CI,Tm,DE,Q,TOP,BOT,N, Tdev,maxdev,ORD) +455 continue do 465 X=1.COL do 460 Z=1,ROW Tm(X,Z) = Tp(X,Z)460 continue 465 continue th = 2*PI*f*time + PI/2. $A = PI^*.250^*((\cos(th))^{**2} + 2^*\cos(th) + 1.)$ rfI = 0.5*(cos(th) + 1.) * Irf*** calculate new RE(I) do 470 X=2,N+1 $RE(X)=Rodet^{(alpha^{(Tm(X,2)-Tamb))+1.)}$ $Q(X) = (Ibias^{**2} + A^*Irf^{**2}) * RE(X)$ 470 continue time = time + DESumRe = 0.0do 475 X=2,N+1 SumRe = SumRe + RE(X)475 continue V=Ibias * SumRe * 2000. *** note: this V is in μ V, for a full length bol ntime = time/DE TV(1.I) = ntimeTV(2,I) = VTV(3,I) = rfI

IF(V.gt.Vmax) THEN Vmax = VRmax = 2*SumReEND IF IF(V.lt.Vmin) THEN Vmin = VRmin = 2 * SumRe**END IF** Write(9,*) ntime, char(9), to time, char(9), SumRe, char(9), V 480 continue W = PI*Irf**2*(Rmax+Rmin)/2.Vpp = Vmax-VminResp = Vpp/WWrite(9, *)' f Vpp W Resp' Write(9,*) f,char(9),Vpp,char(9),W,char(9),Resp *** print out ntime, V and rfI OPEN(UNIT=12,FILE=isofname) Do 490 I=1,DUR*tinc ntime = TV(1,I)V = TV(2,I)rfI = TV(3,I)Write(12,485) ntime,char(9),V,char(9),rfI 485 Format(1x,E12.6,a1,E22.16,a1,E22.16) 490 continue CLOSE(UNIT=12) Vmax = 0.Vmin = 1.D9Write(9,*) char(7)495 Write(9,*) '[0]=new run,[1]=stop' Read(9,*) user GO TO (5,600), user + 1 600 pause 'return to stop' 605 stop end SUBROUTINE INTERP(TLO,TT,THI,ZRLO,ZRT,ZRHI) Real*8 TLO,TT,THI,ZRLO,ZRT,ZRHI If((THI-TLO).eq.0.) then ZRT = ZRLOElse ZRT = ZRLO + ((TT-TLO)/(THI-TLO))*(ZRHI-ZRLO)End If

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RETURN END SUBROUTINE GSITER(ROW,COL,Tp,Zx,Zz,CI,Tm,DE, Q,TOP,BOT,N,Tdev,maxdev,ORD) +INTEGER ROW, COL, X, Z, ORD, N Real*8 Zx(ORD,ORD),Zz(ORD,ORD), CI(ORD,ORD),Tp(ORD,ORD),Q(ORD), +Tm(ORD,ORD), Tdev, maxdev, TOP, BOT, DE + Z = 2DO 10 X=2,N+1 TOP = Q(X) + 2.*Tp(X-1,Z)/(Zx(X,Z)+Zx(X-1,Z)) +2.*Tp(X+1,Z)/(Zx(X,Z)+Zx(X+1,Z)) +++2.*Tp(X,Z-1)/(Zz(X,Z)+Zz(X,Z-1)) +2.*Tp(X,Z+1)/(Zz(X,Z)+Zz(X,Z+1)) ++CI(X,Z)*Tm(X,Z)/DE+BOT = 2./(Zx(X,Z)+Zx(X-1,Z)) +2./(Zx(X,Z)+Zx(X+1,Z)) ++2./(Zz(X,Z)+Zz(X,Z-1)) ++2./(Zz(X,Z)+Zz(X,Z+1)) + CI(X,Z)/DE+Tdev = TOP/BOT - Tp(X,Z)Tdev = ABS(Tdev)Tp(X,Z) = TOP/BOTIF (maxdev .gt. Tdev) go to 10 maxdev = Tdev10 continue DO 40 X=2,COL-1 DO 30 Z=3,ROW-1 TOP = 2.*Tp(X-1,Z)/(Zx(X,Z)+Zx(X-1,Z)) +2.*Tp(X+1,Z)/(Zx(X,Z)+Zx(X+1,Z)) ++2.*Tp(X,Z-1)/(Zz(X,Z)+Zz(X,Z-1)) +++2.*Tp(X,Z+1)/(Zz(X,Z)+Zz(X,Z+1)) +CI(X,Z)*Tm(X,Z)/DE+BOT = 2./(Zx(X,Z)+Zx(X-1,Z)) +2./(Zx(X,Z)+Zx(X+1,Z)) ++2./(Zz(X,Z)+Zz(X,Z-1)) +++2./(Zz(X,Z)+Zz(X,Z+1)) + CI(X,Z)/DETdev = TOP/BOT - Tp(X,Z)Tdev = ABS(Tdev)Tp(X,Z) = TOP/BOTIF (maxdev .gt. Tdev) go to 30 maxdev = Tdev30 continue

40 continue RETURN END

Appendix B ROUTINE PHOTOLITHOGRAPHY

1. Pre-clean

a. Clean slides in acetone, ethanol, high purity water (HPH $_2$ O). Bake dry.

b. Full power O₂ plasma, 5 minutes. (O₂ at 600 mtorr, glass chamber;

precede with a 5 minute O_2 flush).

- c. Rinse in HPH₂O.
- d. Dry at 125°C for at least 15 minutes.

2. Spin-on primer and photoresist

a. Apply adhesion promoter.

- apply enough to thoroughly cover chip
- let stand 10 seconds before spinning
- spin at 4000 rpm for 30 seconds
- b. Apply 1350J-SF photoresist (4000 rpm, 30 sec).

3. Pre-bake

a. Bake for 25 minutes at 85°C.

4. Expose

a. Expose for 85 sec through mask.

• at radiation power of 2.5 mW/cm² incident on top of mask.

5. Develop

- a. Develop in Shipley 452 developer for 60 sec; gentle agitation. Double diprinse in HPH₂O.
- b. Blow dry.
- 6. Flood expose

a. Expose entire chip for 85 seconds.

7. Postbake

a. Bake at 125°C for 10 minutes.

Note: I usually skip the flood exposure step.

Appendix C ELECTROPLATING

This procedure has been used to electroplate gold contacts to chips and printed circuit boards. The procedure was initially outlined in <u>High Frequency</u> <u>Characteristics of Tape Automated Bonding</u> (S.M. Wentworth, Masters Thesis, The University of Texas at Austin, 1987) as a method for electroplating gold bumps on a test chip.

1. Set up the electroplating apparatus as shown in Fig. A.1.

- since the plating solution evolves cyanide gas, apparatus must be set up in a properly ventilated hood.
- 2. Warm the electroplate solution to 55-60 °C.
 - where practical, use a magnetic stirrer set at low speed.
 - use OROTEMP gold plating solution. This is a pH neutral solution.

Previous attempts to electroplate using a basic pH electroplate solution resulted in damage to the photoresist mask during the plate.

3. Optimum plating calls for 10 A/ft^2 . Most of our chips are small, with small plate areas. Usually 1-2 mA current is sufficient.

4. Plating for a duration of 30-40 minutes should result in a 10-20 μ m thick gold layer.

Other comments:

- reversing polarity makes a good gold etcher.
- for critical applications where high quality gold pads are required, use a relatively large quantity of fresh plating solution.
- do not discard solution (it is expensive). Used solution can generally be reused in non-critical plating steps (like plating PCBs). Discard solution only after current quits flowing through it.

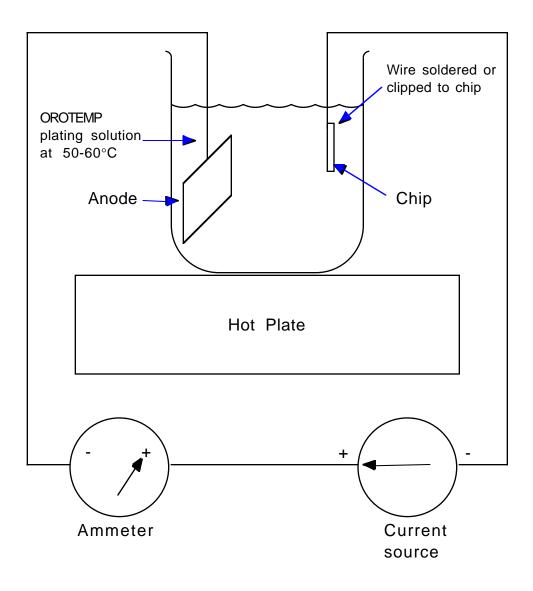


Fig. C.1: Electroplating setup.

Appendix D CF₄ PLASMA PROCESS

This is a bi-layer resist process useful for doing lift-off and for forming photoresist bridges. It seems more reliable than the chlorobenzene soak process, but is more time consuming. The process utilizes two March Insruments (formerly Tegal) plasma chambers. These are table top barrel reactors designed for educational/research use. For operation, they require a mechanical vacuum pump and regulated gas sources.

Since reactive CF_4 etches glass, the pyrex cylinder in one of the units was replaced with an all teflon chamber. Within this chamber, samples were placed upon a perforated teflon plate. The substrate used to optimize this procedure was glass slide. This procedure works best with no more than 2 sq. inches total of substrate surface area, as there appears to be a loading effect in the teflon chamber when a larger area substrate is used.

1. Pre-Clean

a. Clean slides in acetone, ethanol, H₂O. Bake dry.

b. Full power O₂ plasma, 5 minutes. (O₂ at 600 mtorr, glass chamber;

precede with a 5 minute O_2 flush).

c. Note that each plasmod has its own vacuum gauge.

d. You may need to skip this step if the chip already has a metal pattern on it (Au is okay, but Cr or Ag will oxidize).

2a. Photolith 1

a. Apply adhesion promoter

• apply enough to thoroughly cover chip

- let stand 10 seconds before spinning
- spin at 4000 rpm for 20 seconds
- b. Apply 1350J-SF photoresist (4000 rpm, 20 sec).

c. Pre-bake 15 minutes at 75°C.

d. Flood expose chips for 70 sec.; pause and blow off chips; expose another 70 sec.

• Power incident on top of the mask from the HTG aligner is measured as 2.75mW/cm².

2b. TFE Chamber Preparation

a. While baking photoresist in step 2, evacuate the TFE chamber and flush with CF₄ for 5 minutes.

b. Run CF₄ plasma at setting 5.0 for ~3 minutes (see step 3).

• This "preps" the chamber and greatly improves run-to-run uniformity.

• This TFE plasmod will tend to drift in power, so continuous monitoring of the power is necessary. The fuse may blow if the needle pegs out.

3. CF_4 plasma

a. Place each chip in one of the 4 central-most squares scribed into the TFE flat support plate.

• chip placement in the chamber may be important.

b. Flush TFE chamber 5 minutes with 400 mtorr CF₄.

• it is important to remove <u>all</u> oxygen from the chamber to avoid pinholes.

• have had success with as little as 2 minutes of flush.

c. CF₄ plasma, **3** minutes at dial setting 5.0 (CF₄ @ 400 mtorr).

• This TFE plasmod will tend to drift in power, so continuous monitoring of the power is necessary. The fuse may blow if the needle pegs out.

• CF₄ plasma gives off a purplish glow.

d. Flush chamber 1 minute with 600 mtorr CF₄.

• this step is to protect the operator from possibly harmful gasses.

4. N₂ plasma roughing

a. Flush glass chamber at least 5 minutes with 600 mtorr N_2 .

• it is critical that all O_2 be removed from the chamber. The

fluorinized buffer layer is very thin and easily damaged by reactive O_2 .

• have had success with only 2 minutes of flush.

b. Full power N_2 plasma, **25** seconds ($N_2 @ 600$ mtorr).

• N_2 plasma is necessary in order to get 2nd layer Photoresist to stick. If it doesn't stick, increase plasma time.

• too much N_2 plasma will put pinholes in the buffer layer. If pinholes are evident, decrease plasma time.

• N₂ plasma gives off a pinkish-red glow.

5. Photolith 2

a. Skip the adhesion promotion step.

• this step may damage the buffer layer.

since this step is skipped, the 2nd photolith step needs to be done very soon after the N₂ roughing step, before moisture is absorbed.
b. Apply 1350J photoresist (4000 rpm, 20 seconds) (or 1350J-SF)

c. Prebake 20 minutes at 75 °C.

d. Expose through mask for 90 seconds at 6" contact vacuum.

e. Develop in 452 developer for 45-60 sec; gentle agitation. Double dip-rinse in HPH_2O .

• do not rinse under flowing water since the film may be damaged.

f. Blow dry.

6. Remove Buffer Layer

a. Flush glass chamber 5 minutes with 600 mtorr O₂.

b. Full O₂ plasma, **2** minutes (O₂ @ 600 mtorr).

• too much O₂ plasma may damage top layer and round corners.

• O₂ plasma gives off a blueish glow.

7. Etch Bottom Resist Layer

a. Etch for **45-60** seconds, gentle agitation, 452 developer.

• adjust etch to give desired undercut

b. Double dip-rinse in HPH₂O.

c. Gently blow-dry.

• Do not allow the chip to get hot after this step. I have seen the lip deform with as little as 5 min of 90°C heat.

• If all went well, your photoresist should appear very smooth at 400X magnification, and the overhang should be visible and consistent. Some slight roughness may be noted along the edges.

• A problem occasionally seen here by me and Bubba is what is thought to

be pieces of residual buffer layer scattered about the chip (it will look like saran wrap under magnification).

8. (optional) Clean exposed surface.

a. Flush glass chamber 5 minutes with $600 \text{ mtorr } O_2$.

b. Full power O₂ plasma, 1 minute (O₂ @ 600 mtorr).

8. Metal deposition

9. Lift-off in acetone

Appendix E STUVAC OPERATION

The STUVAC vacuum system in general consists of a roughing pump, a diffusion pump stack, a cryo-trap, and an 18" diameter, 18" tall glass cylinder. Materials can be evaporated from one of three e-gun hearths. Samples are place on a rotatable, tiltable, sample holder which is mounted on the top plate.

The following is a brief checklist to be followed whenever using the STUVAC vacuum system. This is <u>not</u> intended to be an operations manual for first time users of the system, but instead serves as a reminder of important things to do and not to do when operating STUVAC for people who are experienced users. The first time user of the system should be supervised through the process, as many 'glitches' in operation are better described physically rather than orally.

- _____ 1. Check XTAL monitor and turn on cylinder heat.
- _____ 2. Switch the auto/manual switch to auto. Press stop.
- _____ 3. Open both pneumatic and manual vents. The pneumatic vent by itself is very slow.
 - make sure the e-gun power supply is <u>locked</u> in the <u>off</u> position.
- 4. After cylinder comes up to atmospheric pressure, lift the top plate pivot rod, and carefully open the top plate.

• check the boot around the top of the cylinder. It will sometimes come loose here.

_____ 5. Carefully raise the cylinder.

• watch cables and pulleys.

• do not raise too high! There is no 'safety' stop feature when raising the cylinder. I usually raise it until there is only about 3" of cable below the pulley.

6. Remove chimney, source cover, and magnet shunt bar.

• wear gloves and a mask.

- _____ 7. Load samples and note their location in the logbook.
- 8. Install window, replace source cover and chimney.
- _____ 9. Carefully lower the cylinder.
- _____ 10 Load the sample holder.
- _____ 11. Close the top plate and lower the top plate pivot rod.
- _____ 12. Close all valves and inspect the top boot.
- _____ 13. Switch system to the auto mode and press start.
 - there should be a 3-5 minute pump down before valves automatically switch.
- _____ 14. Fill the liquid nitrogen trap.
- ____ 15. Let system pump down for <u>at least</u> 45 minutes.
- _____ 16. Turn on the crystal monitor water, the e-gun water, and the ion gauge.
- _____ 17. Position the appropriate source.
- 18. Unlock the e-gun switch, and turn on the e-gun.
 - for safety sake, do not unlock the e-gun unless both PHILVAC and
 - STUVAC are closed and under vacuum.
 - make sure cables are connected to STUVAC.
 - make sure interlock is switched to STUVAC.
- _____ 19. Turn on the crystal monitor and enter appropriate settings.
 - make sure XTAL Monitor selector is set to STUVAC.
- _____ 20. Heat up the source, and set evaporation rate.
 - only open shutter enough to expose XTAL monitor head.
- _____ 21. Open the shutter and evaporate.
- _____ 22. Turn off the e-gun and close shutter.
- ____ 23. For other sources, repeat step 17,19-22.
- _____ 24. Turn off the e-gun and lock out the switch.
- _____ 25. Turn off the crystal monitor, and crystal monitor water.
- ____ 26. Allow 10 minutes of cooling off time, then turn off the e-gun cooling water.
- ____ 27. Turn off the ion gauge.
- _____ 28. In auto mode, press stop.
- _____ 29. Open the manual vent, and turn off cylinder heat.

- _____ 30. After cylinder comes up to atmospheric pressure, lift the top plate pivot rod, and carefully open the top plate.
- _____ 31. Carefully remove sample from sample holder.
- _____ 32. Carefully raise the cylinder.
- 33. Remove chimney, source cover, and discard coated window.
- _____ 34. Remove sources and replace magnet shunt bar.
- _____ 35. Install new window, replace source cover and chimney.
- _____ 36. Carefully lower the cylinder.
- _____ 37. Close the top plate, and lower the pivot bar.
- _____ 38. Close the manual vent valve.
- _____ 39. In auto mode, press start.
- _____ 40. After pumping system down for about 10 minutes, set system to standby state:

manual mode; only foreline valve open. May have to toggle this valve switch to get it to open.

VITA

Stuart Martin Wentworth was born in Pensacola, Florida, on February 17, 1959, the son of Betty Joyce Wentworth and Martin Goodlough Wentworth. After graduating from Escambia High School, Pensacola, Florida, he attended Pensacola Junior College from 1977 to 1979. In March 1979, he entered Auburn University in Auburn, Alabama. In September of 1981, he wed Julie Leona Welch and returned with her to Auburn where he graduated with highest honors and a Bachelor's degree in Chemical Engineering. During the following years he was employed as a quality control engineer for Du Pont at Old Hickory, Tennessee. In January, 1985, he entered the Graduate School of The University of Texas at Austin. He received the degree of Master of Science in Engineering in August, 1987, and was admitted to candidacy in the Doctoral program at The University of Texas at Austin in July, 1988.

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